ABSTRACT

The present disclosure relates to a testing head (1) with vertical probes for a probe card (4) comprising:

- at least one pair of support and guide plates (20, 30) arranged parallel to each other in a prefixed spaced apart relation and provided with a plurality of guide and housing holes (15, 35);

- a plurality of contact probes (14) housed and extended between corresponding holes (15, 35) of the guide plates (20, 30); as well as

- at least one additional plate (23, 33) slidingly mounted next to one (20) or the other (30) of the guide plates (20, 30) and provided with one corresponding plurality of holes (45) of the guide plates (20, 30).

The disclosure also relates to a method of assembly of said testing head (1)

(Fig. 2)